

## 650V GaN FET

### 1. Description

The G2N65 series FETs are hybrid normally-off Gallium Nitride (GaN) field effect transistors with the strongest gate and the lowest reverse voltage drop of all wide-band-gap devices in the market. They allow simple gate drive, offer best-in-class performance and outstanding reliability.

#### Features

- Strong gate with a high threshold, no need for negative gate drive, and a high repetitive input voltage tolerance of  $\pm 20V$ .
- Fast turn-on/off speed for reduced cross-over losses.
- Low  $Q_g$  and simple gate drive for lowest driver consumption at high frequencies.
- Lowest  $V_F$  in off-state reverse conduction among all SiC and GaN FETs for low loss during dead-times.
- Negligible  $Q_{rr}$  for outstanding hard-switched bridge applications.
- High spike tolerance of 800V for enhanced reliability.

#### Benefits

- Enable very high conversion efficiencies.
- Enable higher frequency for compact power supplies.
- End-product cost & size savings due to reduced cooling requirements.
- Improved safety & reliability due to cooler operation temperature.
- Higher output power due to the best efficiency and thermal capability.

#### Applications

- Half-bridge buck/boost, totem-pole PFC circuits or inverter circuits.
- High-efficiency/High-frequency phase-shift, LLC or other soft-switching topologies.

Key Performance Parameters	
$V_{DSS}$ (V)	650
$V_{DSS(PK)}$ , nonrepetitive (V) <sup>a)</sup>	800
$V_{DSS(PK)}$ , repetitive (V) <sup>b)</sup>	750
$R_{DS(on)}$ , typ (m $\Omega$ ) <sup>c)</sup>	35
$Q_{oss}$ (nC)	150
$Q_g$ (nC)	38

<sup>a)</sup> Duty cycle < 1%, spike duration < 30 $\mu$ s, nonrepetitive

<sup>b)</sup> Duty cycle < 1%, spike duration < 30 $\mu$ s, repetitive

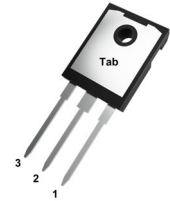
<sup>c)</sup> Dynamic on-resistance

Part Number & Package Information		
Part #	Package	Package Base
G2N65R035TB-H	TO-247-3L	Source

### Datasheet Preliminary

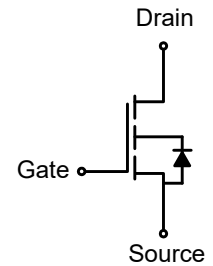


Top View



Bottom View

Gate	1
Source	2, Tab
Drain	3



Schematic Symbol



\*Lead plating Pb-free in compliance with RoHS

## 2. Maximum Ratings

Symbol	Parameter	Value
V <sub>DSS</sub> (V)	Drain-source maximum voltage (T <sub>J</sub> = -55°C to 150°C)	650
V <sub>DSS(PK)</sub> , nonrepetitive (V)	Drain-source maximum peak voltage, nonrepetitive <sup>a)</sup>	800
V <sub>DSS(PK)</sub> , repetitive (V)	Drain-source maximum peak voltage, repetitive <sup>a)</sup>	750
V <sub>GSS, DC</sub> (V)	Gate-source maximum voltage	±20
V <sub>GSS, AC</sub> (V)	Gate-source maximum voltage (f ≥ 50Hz)	±30
P <sub>D</sub> (W)	Maximum power dissipation (T <sub>C</sub> = 25°C)	174
I <sub>DS</sub> (A)	Maximum continuous drain current (T <sub>C</sub> = 25°C)	49.8
	Maximum continuous drain current (T <sub>C</sub> = 100°C)	31.5
I <sub>DS (pulse)</sub> (A)	Maximum pulsed drain current (T <sub>C</sub> = 25°C) <sup>b)</sup>	240
T <sub>J</sub> (°C)	Operating junction temperature	-55 to 150
T <sub>S</sub> (°C)	Storage temperature	-55 to 150
T <sub>Sold</sub> (°C)	Wave-soldering peak temperature <sup>c)</sup>	260
M <sub>d</sub> (N·cm)	Mounting Torque, M3 and M3.5 screws	70

<sup>a)</sup> Duty cycle < 1%, spike duration < 30μs

<sup>b)</sup> Pulse width = 10μs

<sup>c)</sup> For 10 seconds, 1.6mm from the case

## 3. Thermal Characteristics

Symbol	Parameter	Typ.
R <sub>θJC</sub> (°C/W)	Junction-to-case thermal resistance	0.72
R <sub>θJA</sub> (°C/W)	Junction-to-ambient thermal resistance	40

## 4. Device Characteristics

$T_J = 25^\circ\text{C}$  unless specified

Symbol	Parameter	Min.	Typ.	Max.	Unit	Test Conditions
$V_{GS(th)}$	Gate threshold voltage	3.0	3.5	4.0	V	$V_{DS} = V_{GS}$ , $I_D = 4.3\text{mA}$
$R_{DS(on)}$	Drain-source on resistance <sup>a)</sup>	-	35	41	m $\Omega$	$V_{GS} = 10\text{V}$ , $I_D = 30\text{A}$
		-	70	-	m $\Omega$	$V_{GS} = 10\text{V}$ , $I_D = 30\text{A}$ , $T_J = 150^\circ\text{C}$
$I_{DSS}$	Drain-source leakage current	-	3	30	$\mu\text{A}$	$V_{DS} = 650\text{V}$ , $V_{GS} = 0\text{V}$
		-	20	-	$\mu\text{A}$	$V_{DS} = 650\text{V}$ , $V_{GS} = 0\text{V}$ , $T_J = 150^\circ\text{C}$
$I_{GSS}$	Gate-source leakage current	-	-	100	nA	$V_{GS} = 20\text{V}$
		-	-	-100	nA	$V_{GS} = -20\text{V}$
$C_{iss}$	Input capacitance	-	2410	-	pF	$V_{GS} = 0\text{V}$ , $V_{DS} = 400\text{V}$ , $f = 500\text{kHz}$
$C_{oss}$	Output capacitance	-	150	-	pF	$V_{GS} = 0\text{V}$ , $V_{DS} = 400\text{V}$ , $f = 500\text{kHz}$
$C_{rss}$	Reverse transfer capacitance	-	10	-	pF	$V_{GS} = 0\text{V}$ , $V_{DS} = 400\text{V}$ , $f = 500\text{kHz}$
$C_{o(er)}$	Equivalent output capacitance (energy related)	-	220	-	pF	$V_{GS} = 0\text{V}$ , $V_{DS} = 0\text{V}$ to 400V
$C_{o(tr)}$	Equivalent output capacitance (time related)	-	375	-	pF	$V_{GS} = 0\text{V}$ , $V_{DS} = 0\text{V}$ to 400V
$Q_g$	Gate charge total	-	38	-	nC	$V_{DS} = 400\text{V}$ , $V_{GS} = 0\text{V}$ to 10V, $I_D = 30\text{A}$
$Q_{gs}$	Gate to source charge	-	13.3	-	nC	$V_{DS} = 400\text{V}$ , $V_{GS} = 0\text{V}$ to 10V, $I_D = 30\text{A}$
$Q_{gd}$	Gate to drain charge	-	13	-	nC	$V_{DS} = 400\text{V}$ , $V_{GS} = 0\text{V}$ to 10V, $I_D = 30\text{A}$
$Q_{oss}$	Output charge	-	150	-	nC	$V_{GS} = 0\text{V}$ , $V_{DS} = 0\text{V}$ to 400V
$t_{d(on)}$	Turn-on delay time	-	70	-	ns	$V_{DS} = 400\text{V}$ , $V_{GS} = 0\text{V}$ to 10V, $I_D = 30\text{A}$ , $R_G = 18\Omega$ , $Z_{FB} = 120\Omega$ at 100MHz, see Figure 13
$t_r$	Rise time	-	10	-	ns	
$t_{d(off)}$	Turn-off delay time	-	100	-	ns	
$t_f$	Fall time	-	12	-	ns	

<sup>a)</sup> Dynamic on-resistance

Reverse Device Characteristics,  $T_J = 25^\circ\text{C}$  unless specified

Symbol	Parameter	Min.	Typ.	Max.	Unit	Test Conditions
$I_S$	Reverse current	-	-	31.5	A	$V_{GS} = 0V$ , $T_C = 100^\circ\text{C}$ , $\leq 25\%$ duty cycle
$I_S$ (pulse)	Pulsed reverse current	-	-	90	A	$V_{GS} = 0V$ , $V_{SD} = 6V$ , pulse width $\leq 10\mu\text{s}$ , $T_J = 150^\circ\text{C}$
$V_{SD}$	Reverse voltage <sup>a)</sup>	-	1.9	-	V	$V_{GS} = 0V$ , $I_S = 30A$
		-	1.4	-	V	$V_{GS} = 0V$ , $I_S = 15A$
$t_{rr}$	Reverse recovery time	-	41	-	ns	$I_S = 30A$ , $V_{DD} = 400V$ , $di/dt = 1000A/\mu\text{s}$
$Q_{rr}$	Reverse recovery charge <sup>b)</sup>	-	0	-	nC	

<sup>a)</sup> Including the effect of dynamic on-resistance

<sup>b)</sup> Excluding  $Q_{oss}$

## 5. Typical Characteristics ( $T_C = 25^\circ\text{C}$ unless specified)

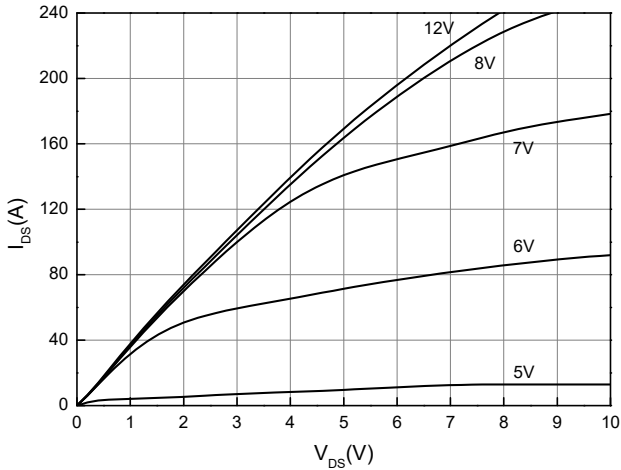


Figure 1. Typical Output Characteristics at  $T_J = 25^\circ\text{C}$   
(Parameter:  $V_{GS}$ )

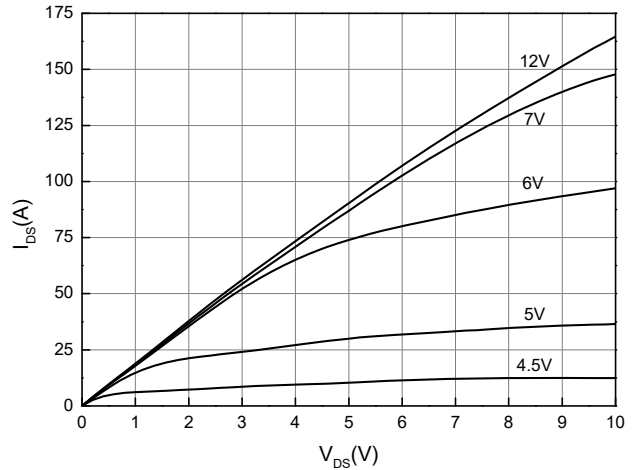


Figure 2. Typical Output Characteristics at  $T_J = 150^\circ\text{C}$   
(Parameter:  $V_{GS}$ )

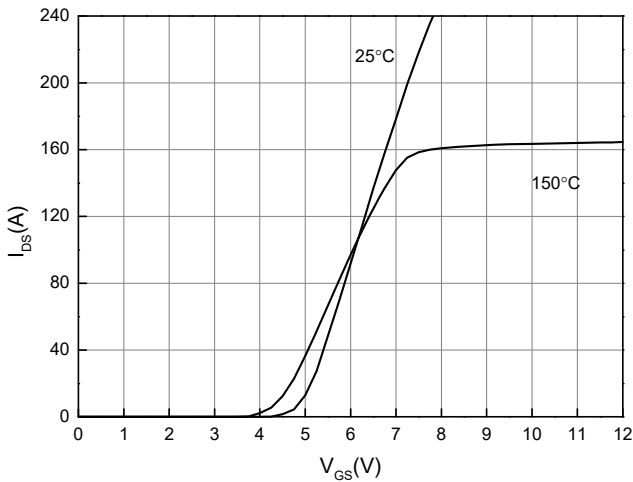


Figure 3. Typical Transfer Characteristics  
( $V_{DS} = 10\text{V}$ , Parameter:  $T_J$ )

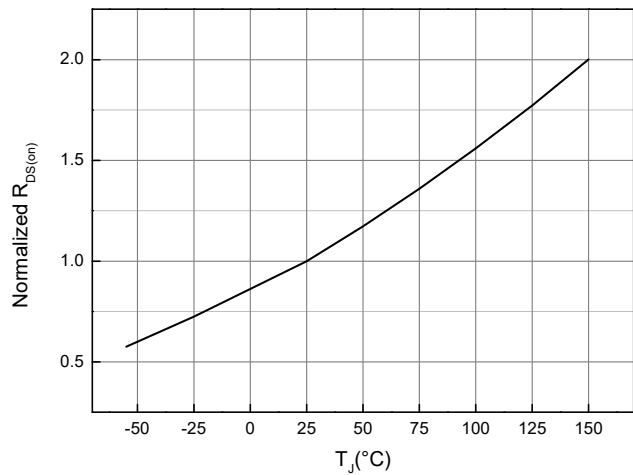
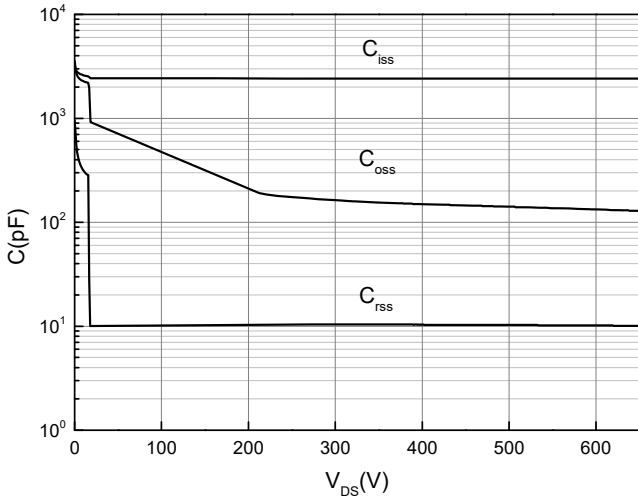
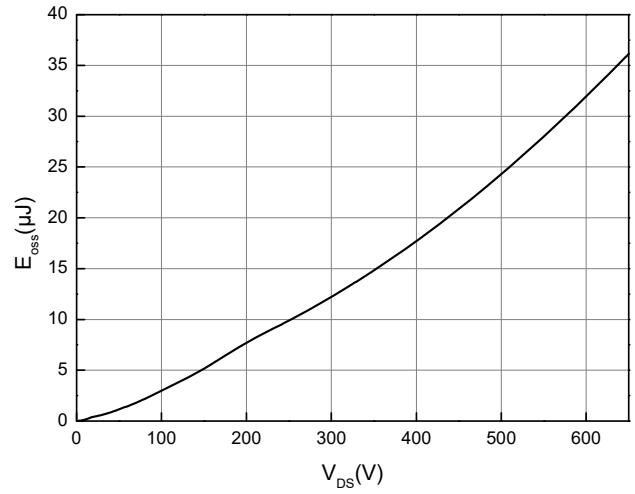


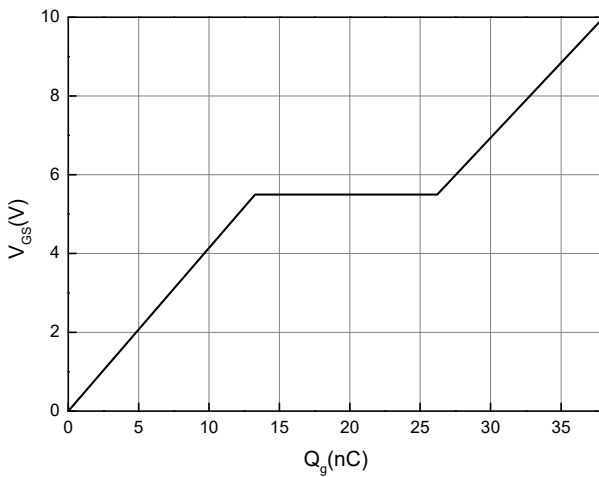
Figure 4. Normalized On-Resistance  
( $I_D = 30\text{A}$ ,  $V_{GS} = 10\text{V}$ )



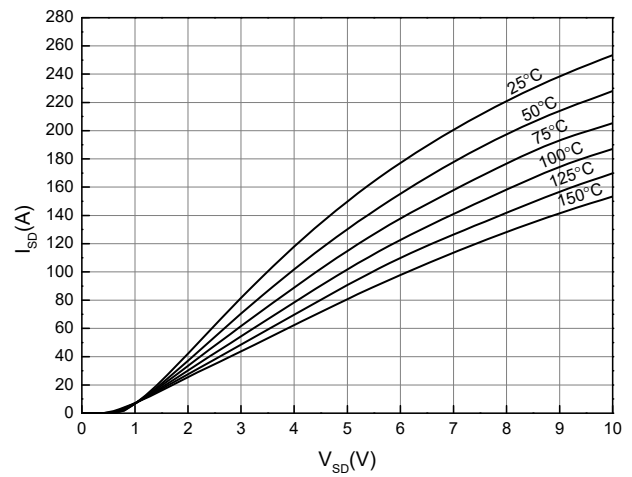
**Figure 5. Typical Capacitance**  
( $V_{GS} = 0V, f = 500kHz$ )



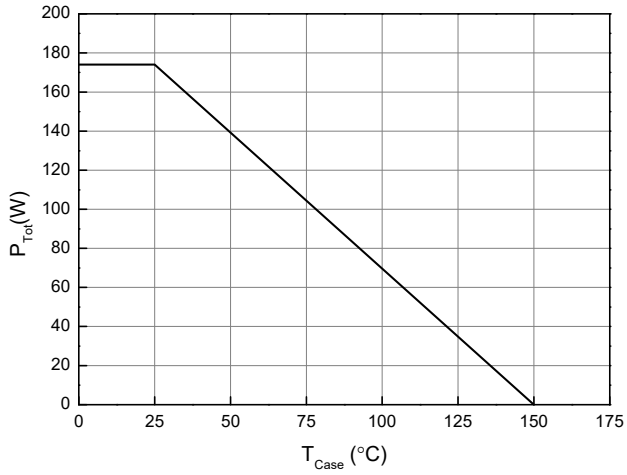
**Figure 6. Typical  $C_{oss}$  Stored Energy**



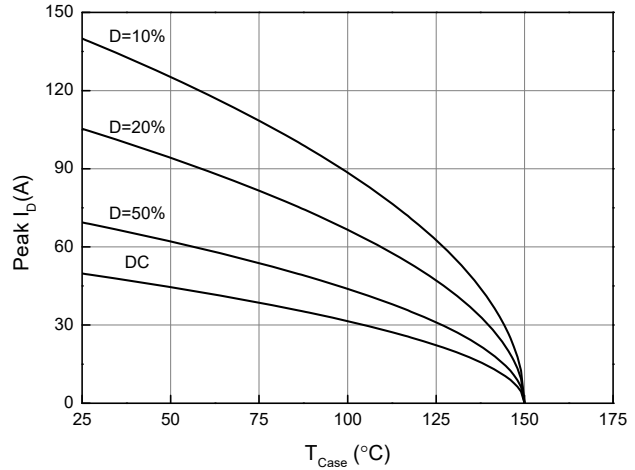
**Figure 7. Typical Gate Charge**  
( $I_{DS} = 30A, V_{DS} = 400V$ )



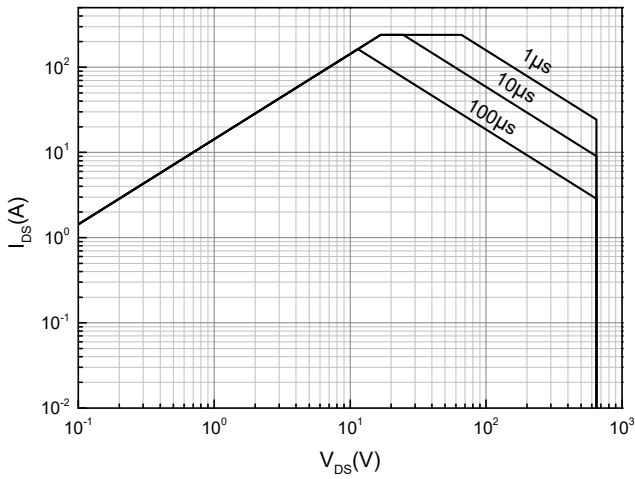
**Figure 8. Reverse Conduction Characteristics**  
( $-20V \leq V_{GS} \leq 0V$ , Parameter:  $T_J$ )



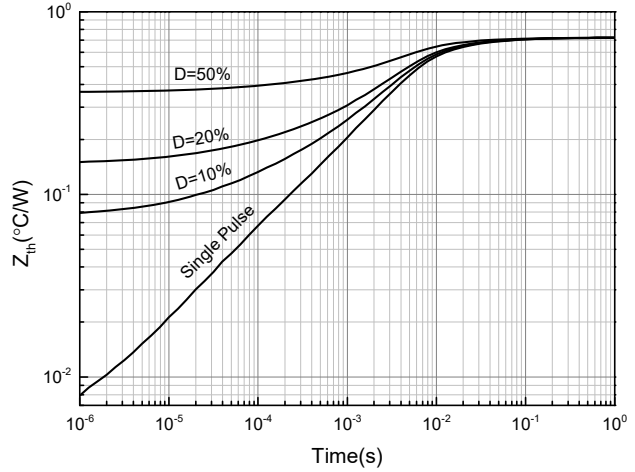
**Figure 9. Power Dissipation**



**Figure 10. Current Derating**  
( Pulse Width ≤ 10μs, V<sub>GS</sub> ≥ 10V )



**Figure 11. Safe Operating Area at T<sub>C</sub> = 25°C**



**Figure 12. Transient Thermal Resistance**

## 6. Design Considerations

The fast switching of GaN devices reduces current-voltage crossover losses and enables high frequency operation while simultaneously achieving high efficiency. However, taking full advantage of the fast switching characteristics of GaN switches requires adherence to specific PCB layout guidelines and probing techniques.

DO	DO NOT
Place gate driver close to the GaN device and separate input traces from output traces	Twist the pins of TO-220 or TO-247 to accommodate GDS board layout
Minimize lead length of TO-220 and TO-247 package when mounting to the PCB	Use long gate drive traces, long lead length and route the output traces next to the input
Use gate ferrite bead and dc-link RC snubber	Use close-by decoupling capacitor without series resistor

## 7. Circuit Implementation

### Half-bridge Schematic

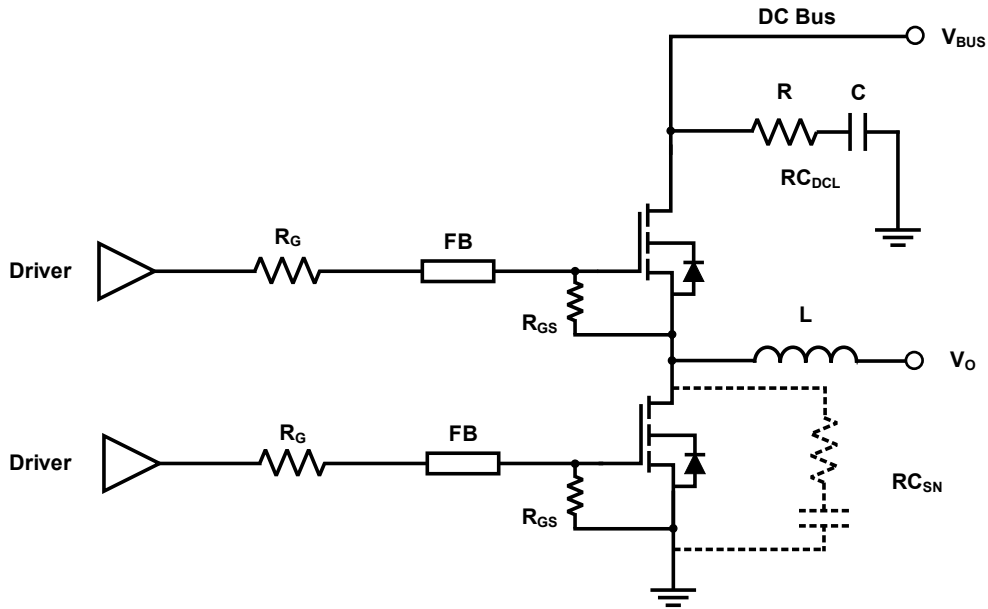


Figure 13. Simplified half-bridge schematic

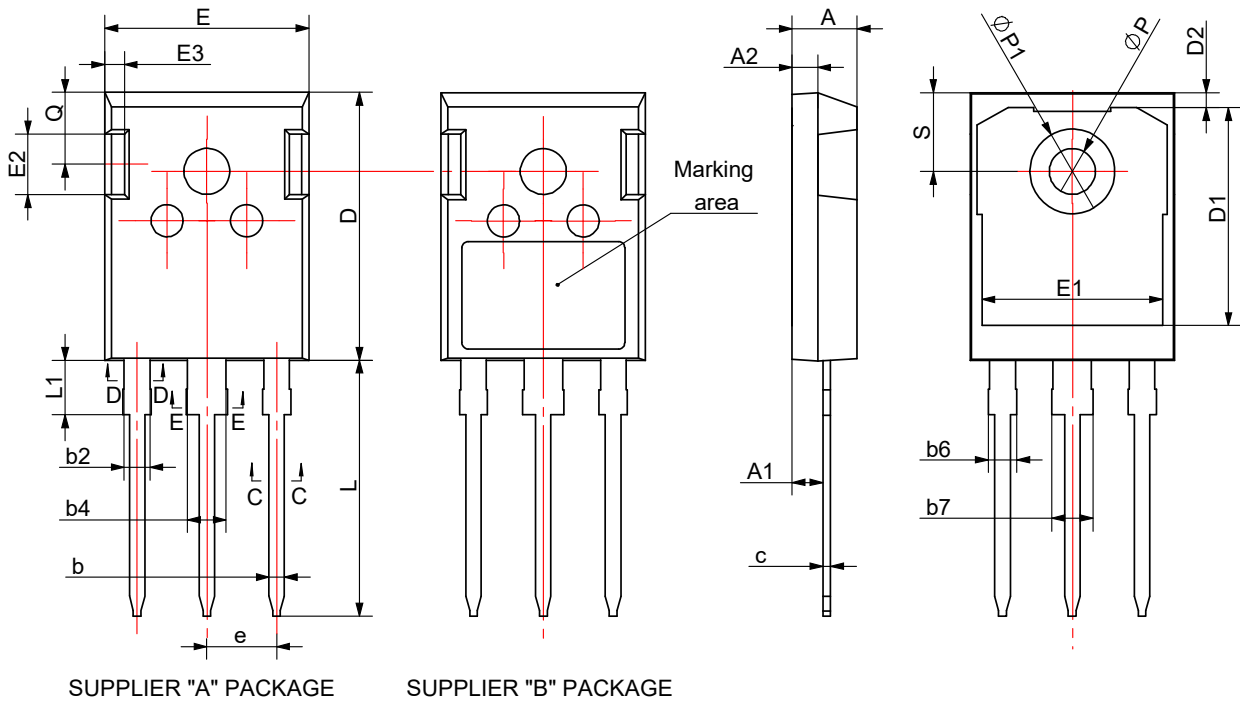
Recommended gate drive: (0V, 12V) with  $R_G = 18\Omega$  <sup>a)</sup>

Gate Ferrite Bead (FB) <sup>b)</sup>	Required DC Link RC Snubber ( $RC_{DCL}$ ) <sup>c)</sup>	Recommended Switching Node RC Snubber ( $RC_{SN}$ )
120-180 $\Omega$ @ 100MHz	$(10-20\text{nF} + 3-5\Omega) \times 2$	Not necessary, see note d and e below

Notes:

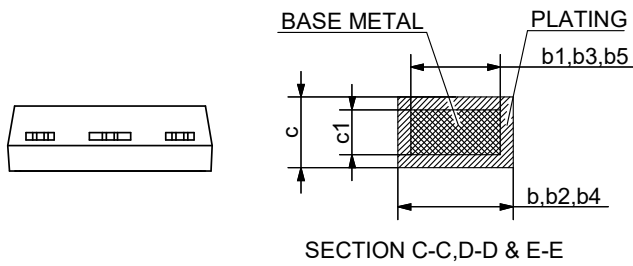
- <sup>a)</sup> For bridge topologies only.  $R_G$  could be smaller in single ended topologies.
- <sup>b)</sup> Examples of material selection: MPZ2012S\*\*\*AT000(TDK), BLM21PG\*\*\*SZ1D(Murata).
- <sup>c)</sup>  $RC_{DCL}$  should be placed as close as possible to the drain pin. Other decoupling capacitor(s) should be located away from the  $RC_{DCL}$ .
- <sup>d)</sup>  $RC_{SN}$  is needed only if  $R_G$  is smaller than recommendations.
- <sup>e)</sup> If required, please use 10 $\Omega$ +100pF.
- <sup>f)</sup> The typical value of  $R_{GS}$  is 10k $\Omega$ .

## 8. Package Dimensions



SUPPLIER "A" PACKAGE

SUPPLIER "B" PACKAGE



**NOTES:**

1. DIMENSIONS D & E NOT INCLUDE MOLD FLASH. MOLD FLASH SHALL NOT EXCEED 0.127 MM PER SIDE. THESE DIMENSIONS ARE MEASURED AT THE OUTERMOST EXTREME OF THE PLASTIC BODY.
2. LEAD FINISH UNCONTROLLED IN L1.
3. OUTLINE CONFORMS TO JEDEC TO-247-AD.

DIM.	Millimeters	
	MIN.	MAX.
A	4.82	5.21
A1	2.20	2.57
A2	1.82	2.18
b	1.07	1.35
b1	1.07	1.30
b2	1.87	2.41
b3	1.87	2.27
b4	2.87	3.38
b5	2.87	3.18
b6	—	2.25
b7	—	3.25
c	0.50	0.68
c1	0.50	0.65
D	20.67	21.11
D1	16.25	17.65
D2	0.81	1.35
E	15.70	16.15
E1	13.10	14.25
E2	3.68	5.10
E3	1.00	2.43
e	5.45BSC	
L	19.55	20.38
L1	3.93	4.48
P	3.40	3.69
P1	7.00	7.40
Q	5.41	6.00
S	6.04	6.30
TO-247-3L		
GaNNext		
DATE: 2022.11		Rev. 03

## 9. Part Marking

